

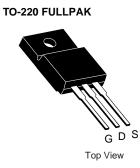
Power MOSFET

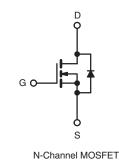
PRODUCT SUMMAI	RY			
V _{DS} (V)	750			
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	1.5		
Q _g (Max.) (nC)	13	30		
Q _{gs} (nC)	1	7		
Q _{gd} (nC)	7:	2		
Configuration	Sin	gle		

FEATURES

- Dynamic dV/dt rating
- Repetitive avalanche rated
- Isolated central mounting hole
- · Fast switching
- Ease of paralleling
- Simple drive requirements







ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	750	v	
Gate-Source Voltage		V _{GS}	± 20	V	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	- I _D	7.0	
		$T_{C} = 100 \ ^{\circ}C$		4.2	A
Pulsed Drain Current ^a I _{DM}		24	1		
Linear Derating Factor			1.2	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	490	mJ	
Repetitive Avalanche Current ^a		I _{AR}	5.4	А	
Repetitive Avalanche Energy ^a		E _{AR}	15	mJ	
Maximum Power Dissipation $T_{C} = 25 \text{ °C}$		PD	65	W	
Peak Diode Recovery dV/dt ^c		dV/dt	2.0	V/ns	
Derating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +150	°C	
Soldering Recommendations (Peak Temperature) ^d	for	10 s		300	
Marine Tanana	6 00 av	10		10	lbf ∙ in
Mounting Torque	6-32 or M3 screw			1.1	N · m

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = 50$ V, starting $T_J = 25$ °C, L = 31 mH, $R_g = 25 \Omega$, $I_{AS} = 5.4$ A (see fig. 12). c. $I_{SD} \le 5.4$ A, dI/dt ≤ 120 A/µs, $V_{DD} \le 600$, $T_J \le 150$ °C.

d. 1.6 mm from case.



THERMAL RESISTANCE RAT	INGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	40	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.83	

PARAMETER	SYMBOL	TEST	CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static		•				•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$	V, I _D = 250 μA	750	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	o 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_0$	_{3S} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	VGS	$s_3 = \pm 20 \text{ V}$	-	-	± 100	nA
ő		-	$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$		-	100	
Zero Gate Voltage Drain Current	IDSS		_{GS} = 0 V, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_{\rm D} = 3.2 \ {\rm A}^{\rm b}$	-	1.5	-	Ω
Forward Transconductance	9 _{fs}		0 V, I _D = 3.2 A ^b	3.0	-	-	S
Dynamic						•	1
Input Capacitance	C _{iss}	$V_{GS} = 0 V,$		-	1900	-	
Output Capacitance	C _{oss}		$_{\rm S} = 25 \rm V,$	-	470	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0 M	/IHz, see fig. 5	-	280	-	
Total Gate Charge	Qq			-	-	130	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	I _D = 5.4 A, V _{DS} = 400 V, see fig. 6 and 13 ^b	-	-	17	nC
Gate-Drain Charge	Q _{gd}		see lig. 6 and 15 *	-	-	72	
Turn-On Delay Time	t _{d(on)}			-	16	-	
Rise Time	t _r	V _{DD} = 40	00 V, I _D = 5.4 A,	-	36	-	
Turn-Off Delay Time	t _{d(off)}	$R_g = 9.1 \Omega$, $R_D = 75 \Omega$, see fig. 10 ^b		-	100	-	- ns
Fall Time	t _f			-	32	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH
Internal Source Inductance	L _S			-	13	-	
Drain-Source Body Diode Characteristic	S	•					
Continuous Source-Drain Diode Current	I _S	MOSFET symbo showing the	MOSFET symbol		-	5	Α
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction dic	ode	-	-	22	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S	$= 5.4 \text{ A}, \text{ V}_{\text{GS}} = 0 \text{ V}^{\text{b}}$	-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	$T_{\rm J} = 25 ^{\circ}\text{C}$, $I_{\rm F} = 5.4 \text{A}$, dl/dt = 100 A/µs ^b		-	550	830	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.4	3.6	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-	on time is negligible (turn	-on is dor	ninated b	by L _S and	L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 $\mu s;$ duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

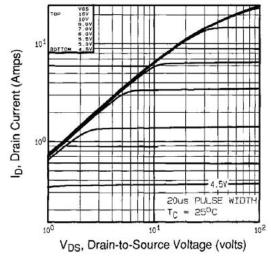


Fig. 1 - Typical Output Characteristics, $T_C = 25 \ ^{\circ}C$

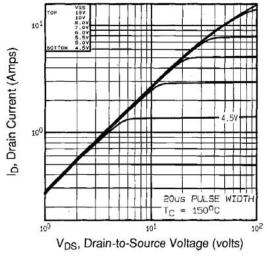


Fig. 2 - Typical Output Characteristics, $T_C = 150 \ ^\circ C$

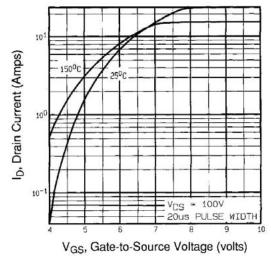


Fig. 3 - Typical Transfer Characteristics

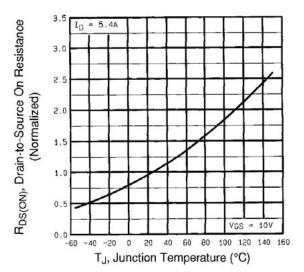


Fig. 4 - Normalized On-Resistance vs. Temperature

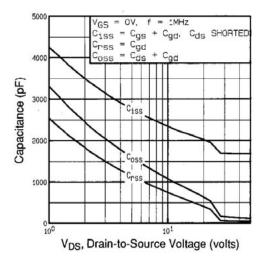
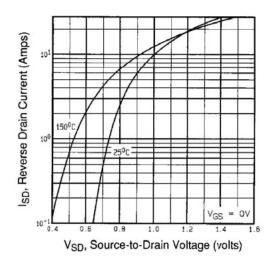


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



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Fig. 7 - Typical Source-Drain Diode Forward Voltage

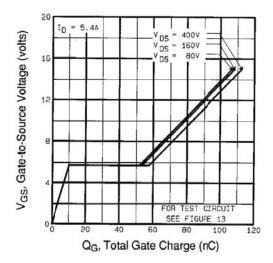


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

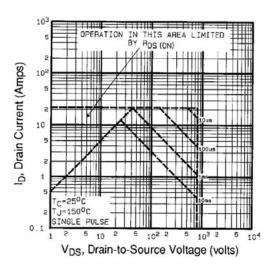


Fig. 8 - Maximum Safe Operating Area

VBMB175R07



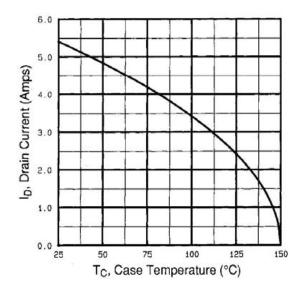


Fig. 9 - Maximum Drain Current vs. Case Temperature

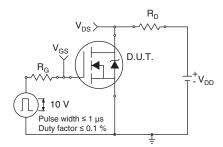


Fig. 10a - Switching Time Test Circuit

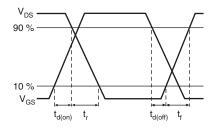


Fig. 10b - Switching Time Waveforms

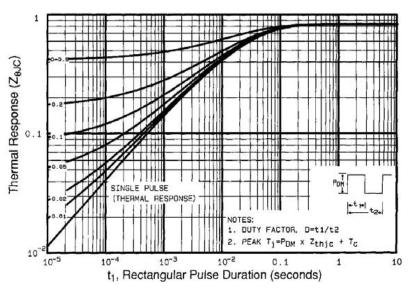


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



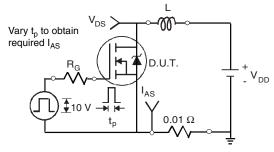


Fig. 12a - Unclamped Inductive Test Circuit

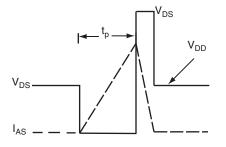
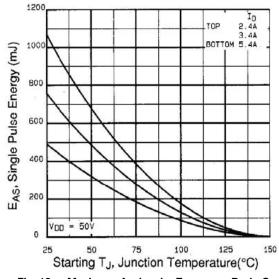
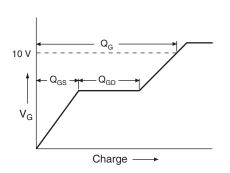


Fig. 12b - Unclamped Inductive Waveforms









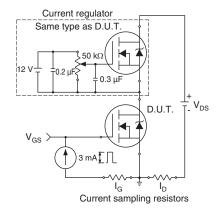
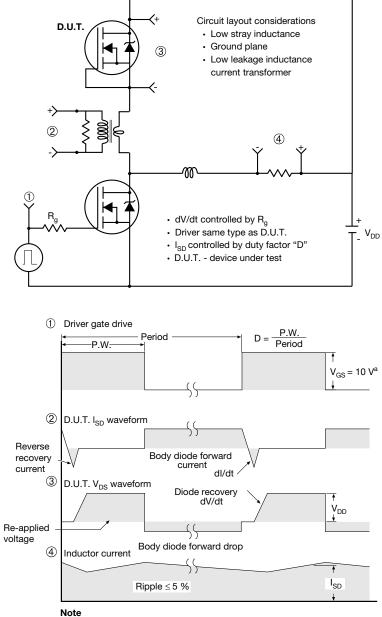


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

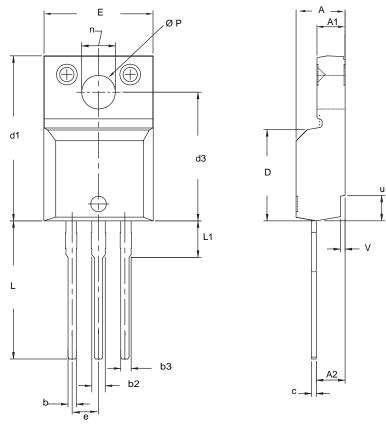


a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



DIM.	MILLIN	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
А	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
С	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54	BSC	0.100	BSC	
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
Ø P	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness. 5. No chipping or package damage.



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